

**Search Notes**

Application/Control No.

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Examiner

Jinhee J. Lee

Applicant(s)/Patent under  
Reexamination

SHIN ET AL.

Art Unit

2175

**SEARCHED**

Class	Subclass	Date	Examiner

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Plus search	2/19/2008	LEE
East text search	5/10/2008	LEE